

STS5DNE30L

PRELIMINARY DATA

N - CHANNEL 30V - 0.039Ω - 5A SO-8 STripFETTM POWER MOSFET

TYPE	V _{DSS}	R _{DS(on)}	ID
STS5DNE30L	30 V	< 0.045 Ω	5 A

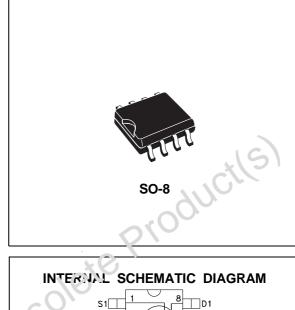
- TYPICAL R_{DS(on)} = 0.039 Ω
- STANDARD OUTLINE FOR EASY AUTOMATED SURFACE MOUNT ASSEMBLY
- LOW THRESHOLD DRIVE

DESCRIPTION

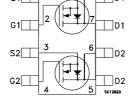
This Power MOSFET is the latest development of STMicroelectronics unique " Single Feature Size™ " strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore remarkable manufacturing а reproducibility.

APPLICATIONS

- DC MOTOR DRIVE
- DC-DC CONVERTERS
- BATTERY MANAGMENT IN NOMADIC EQUIPMENT
- POWER MANAGEMENT IN PORTABLE/DESKTOP PCs







ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
VDS	Drain-source Voltage (V _{GS} = 0)	30	V
VDGR	Drain- gate Voltage (R_{GS} = 20 k Ω)	30	V
د v G	Gate-source Voltage	± 20	V
ID	Drain Current (continuous) at Tc = 25 °C Single Operation Drain Current (continuous) at T _c = 100 °C Single Operation	5 3.1	A
I _{DM} (●)	Drain Current (pulsed)	20	А
P _{tot}	Total Dissipation at $T_c = 25$ °C Dual Operation Total Dissipation at $T_c = 25$ °C Sinlge Operation	2 1.6	W W

(•) Pulse width limited by safe operating area

December 1998

THERMAL DATA

R _{thj-amb}	*Thermal Resistance Junction-ambient	Single Operation	78	°C/W
		Dual Operation	62.5	°C/W
Tj	Maximum Operating Junction Temperatu	ire	150	°C
Tstg	Storage Temperature		-55 to 150	°C

(*) Mounted on FR-4 board (t $\leq 10 \text{sec}$)

ELECTRICAL CHARACTERISTICS ($T_{case} = 25 \ ^{\circ}C$ unless otherwise specified) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
$V_{(BR)}$ dss	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A$ $V_{GS} = 0$	30			V
IDSS	Zero Gate Voltage Drain Current (V _{GS} = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating$ $T_c = 125 °C$			1 10	μΑ μΑ
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	$V_{GS} = \pm 20 V$			± 100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 250 \ \mu A$	1	1.7	2.5	V
R _{DS(on)}	Static Drain-source On Resistance			0.039 0.054	0.045 0.065	Ω Ω
I _{D(on)}	On State Drain Current	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $V_{GS} = 10 V$	20			A

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (*)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $I_D = 2.5 \text{ A}$		6		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 V$ f = 1 MHz $V_{GS} = 0 V$		TBD		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Time Rise Time			TBD		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 24 \text{ V}$ $I_D = 5 \text{ A} \text{ V}_{GS} = 4.5 \text{ V}$		TBD		nC nC nC

SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _f	0			TBD		ns ns ns

SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (●)	Source-drain Current Source-drain Current (pulsed)				5 24	A A
V _{SD} (*)	Forward On Voltage	$I_{SD} = 5 \text{ A}$ $V_{GS} = 0$			1.2	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 5 A$ di/dt = 100 A/µs V _r = 20 V T _i = 150 °C		TBD		ns
Qrr	Reverse Recovery					nC
	Charge					
I _{RRM}	Reverse Recovery					A
	Current					

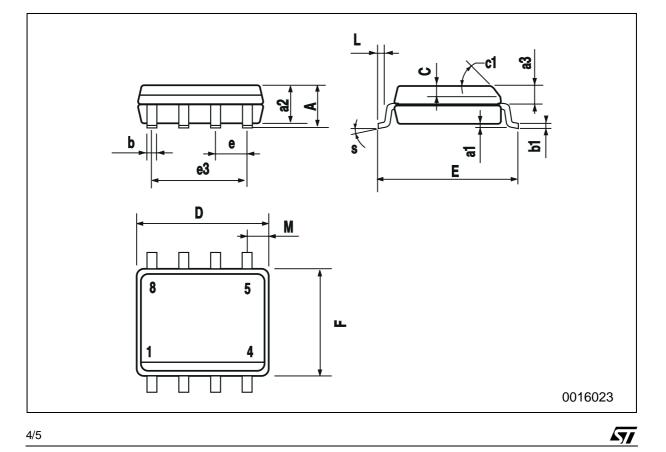
(*) Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %
(•) Pulse width limited by safe operating area



STS5DNE30L

DIM.	mm			inch			
DIM.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А			1.75			0.068	
a1	0.1		0.25	0.003		0.009	
a2			1.65			0.064	
a3	0.65		0.85	0.025		0.033	
b	0.35		0.48	0.013		0.018	
b1	0.19		0.25	0.007		0.010	
С	0.25		0.5	0.010		0.019	
c1			45 ((typ.)			
D	4.8		5.0	0.188		0.196	
Е	5.8		6.2	0.228		0.244	
е		1.27			0.050		
e3		3.81			0.150		
F	3.8		4.0	0.14		0.157	
L	0.4		1.27	0.015		0.050	
М			0.6			0.023	





Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specification mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics. The ST logo is a trademark of STMicroelectronics

5

 $\ensuremath{\mathbb{C}}$ 1998 STMicroelectronics – Printed in Italy – All Rights Reserved

STMicroelectronics GROUP OF COMPANIES

Australia - Brazil - Canada - China - France - Germany - Italy - Japan - Korea - Malaysia - Malta - Mexico - Morocco - The Netherlands -Singapore - Spain - Sweden - Switzerland - Taiwan - Thailand - United Kingdom - U.S.A.

http://www.st.com